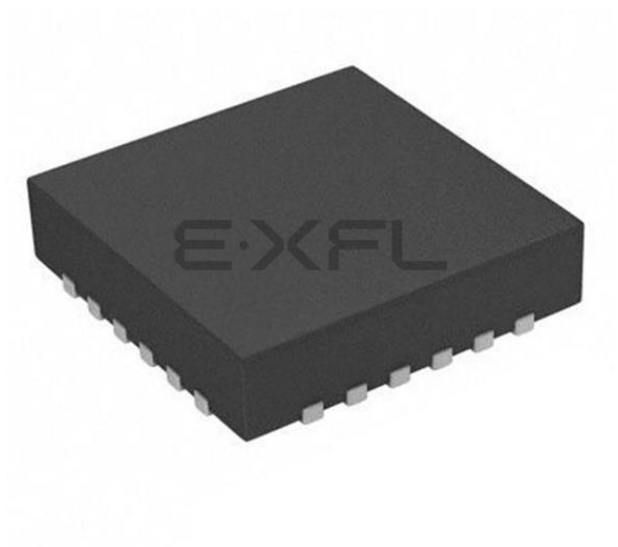

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	20
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x10/12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	24-WFQFN Exposed Pad
Supplier Device Package	24-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb31f64a-b-4qfn24

1. Feature List

The EFM8BB3 device family are fully integrated, mixed-signal system-on-a-chip MCUs. Highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 50 MHz maximum operating frequency
- Memory:
  - Up to 64 kB flash memory (63 kB user-accessible), in-system re-programmable from firmware in 512-byte sectors
  - Up to 4352 bytes RAM (including 256 bytes standard 8051 RAM and 4096 bytes on-chip XRAM)
- Power:
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 29 total multifunction I/O pins:
  - Up to 25 pins 5 V tolerant under bias
  - Selectable state retention through reset events
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 49 MHz oscillator with accuracy of ±2%
  - Internal 24.5 MHz oscillator with ±2% accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
  - External crystal/RC Oscillator (up to 25 MHz)
- Analog:
  - 12/10-Bit Analog-to-Digital Converter (ADC)
  - Internal temperature sensor
  - 4 x 12-Bit Digital-to-Analog Converters (DAC)
  - 2 x Low-current analog comparators with adjustable reference
- Communications and Digital Peripherals:
  - 2 x UART, up to 3 Mbaud
  - SPI™ Master / Slave, up to 12 Mbps
  - SMBus™/I2C™ Master / Slave, up to 400 kbps
  - I^2C High-Speed Slave, up to 3.4 Mbps
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
  - 4 Configurable Logic Units
- Timers/Counters and PWM:
  - 6-channel programmable counter array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 6 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-programmed UART bootloader
- Temperature range -40 to 85 ºC or -40 to 125 ºC

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8BB3 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Device operation is specified from 2.2 V up to a 3.6 V supply. Devices are AEC-Q100 qualified and available in 4x4 mm 32-pin QFN, 3x3 mm 24-pin QFN, 32-pin QFP, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

3. System Overview

3.1 Introduction

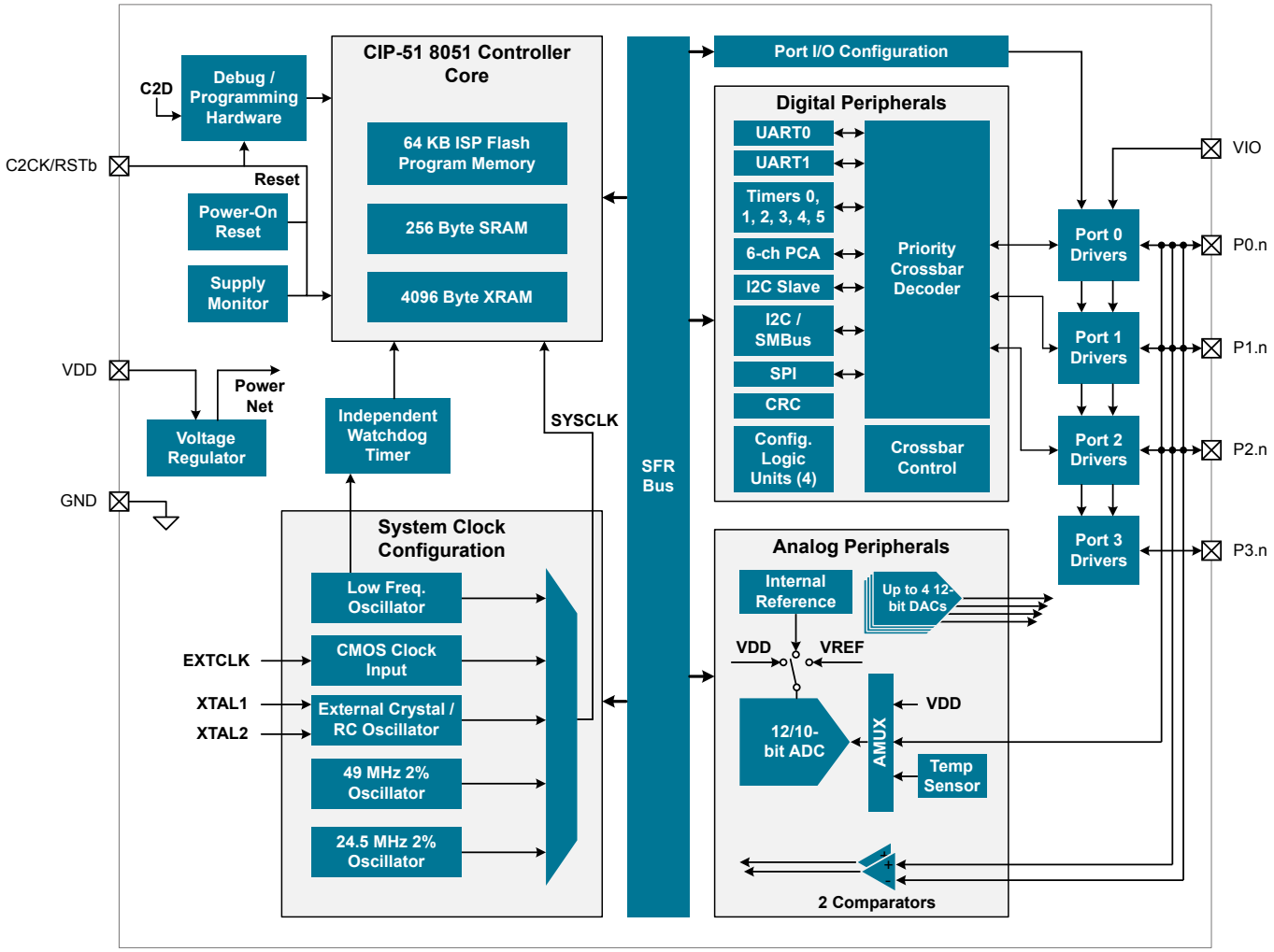


Figure 3.1. Detailed EFM8BB3 Block Diagram

3.7 Analog

12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12- and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 12-bit and 10-bit modes
- Supports an output update rate of up to 350 ksps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated temperature sensor

12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Supports an update rate of 200 ksps
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

Table 3.3. Summary of Pins for Bootload Mode Entry

Device Package	Pin for Bootload Mode Entry
QFN32	P3.7 / C2D
QFP32	P3.7 / C2D
QFN24	P3.0 / C2D
QSOP24	P3.0 / C2D

4.1.8 Crystal Oscillator

Table 4.8. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	—	25	MHz
Crystal Drive Current	I_{XTAL}	XFCN = 0	—	0.5	—	µA
		XFCN = 1	—	1.5	—	µA
		XFCN = 2	—	4.8	—	µA
		XFCN = 3	—	14	—	µA
		XFCN = 4	—	40	—	µA
		XFCN = 5	—	120	—	µA
		XFCN = 6	—	550	—	µA
		XFCN = 7	—	2.6	—	mA

4.1.9 ADC

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	10 Bit Mode	—	—	1.125	Msps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	340	ksps
		10 Bit Mode	—	—	360	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode	—	—	18	MHz
		Low Power Mode	—	—	12.25	MHz
Conversion Time[1]	t_{CNV}	12-Bit Conversion, SAR Clock = 6.125 MHz, System Clock = 49 MHz		2.0		µs
		10-Bit Conversion, SAR Clock = 16.33 MHz, System Clock = 49 MHz		0.658		µs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5.2	—	pF
		Gain = 0.75	—	3.9	—	pF
		Gain = 0.5	—	2.6	—	pF
		Gain = 0.25	—	1.3	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{IO}	V
Input Voltage Range[2]	V_{IN}		0	—	V_{REF} / Gain	V
Power Supply Rejection Ratio	$PSRR_{ADC}$	At 1 kHz	—	66	—	dB
		At 1 MHz	—	43	—	dB
DC Performance						

4.1.10 Voltage Reference

Table 4.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}		1.62	1.65	1.68	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
On-chip Precision Reference						
Valid Supply Range	V_{DD}	1.2 V Output	2.2	—	3.6	V
		2.4 V Output	2.7	—	3.6	V
Output Voltage	V_{REFP}	1.2 V Output, V_{DD} = 3.3 V, T = 25 °C	1.195	1.2	1.205	V
		1.2 V Output	1.18	1.2	1.22	V
		2.4 V Output, V_{DD} = 3.3 V, T = 25 °C	2.39	2.4	2.41	V
		2.4 V Output	2.36	2.4	2.44	V
Turn-on Time, settling to 0.5 LSB	t_{VREFP}	4.7 µF tantalum + 0.1 µF ceramic bypass on VREF pin	—	3	—	ms
		0.1 µF ceramic bypass on VREF pin	—	100	—	µs
Load Regulation	LR_{VREFP}	VREF = 2.4 V, Load = 0 to 200 µA to GND	—	8	—	µV/µA
		VREF = 1.2 V, Load = 0 to 200 µA to GND	—	5	—	µV/µA
Load Capacitor	C_{VREFP}	Load = 0 to 200 µA to GND	0.1	—	—	µF
Short-circuit current	ISC_{VREFP}		—	—	8	mA
Power Supply Rejection	$PSRR_{VREFP}$		—	75	—	dB
External Reference						
Input Current	I_{EXTREF}	ADC Sample Rate = 800 ksps; VREF = 3.0 V	—	5	—	µA

4.1.15 Port I/O

Table 4.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	I_{OH} = -7 mA, V_{IO} ≥ 3.0 V	V_{IO} - 0.7	—	—	V
		I_{OH} = -3.3 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (High Drive)	V_{OL}	I_{OL} = 13.5 mA, V_{IO} ≥ 3.0 V	—	—	0.6	V
		I_{OL} = 7 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 3.6 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Output High Voltage (Low Drive)	V_{OH}	I_{OH} = -4.75 mA, V_{IO} ≥ 3.0 V	V_{IO} - 0.7	—	—	V
		I_{OH} = -2.25 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.2 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (Low Drive)	V_{OL}	I_{OL} = 6.5 mA, V_{IO} ≥ 3.0 V	—	—	0.6	V
		I_{OL} = 3.5 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Input High Voltage	V_{IH}		0.7 x V_{IO}	—	—	V
Input Low Voltage	V_{IL}		—	—	0.3 x V_{IO}	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current (V_{IN} = 0 V)	I_{PU}	V_{DD} = 3.6	-30	-20	-10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	GND < V_{IN} < V_{IO}	-1.1	—	4	µA
Input Leakage Current with V_{IN} above V_{IO}	I_{LK}	V_{IO} < V_{IN} < V_{IO}+2.5 V Any pin except P3.0, P3.1, P3.2, or P3.3	0	5	150	µA

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

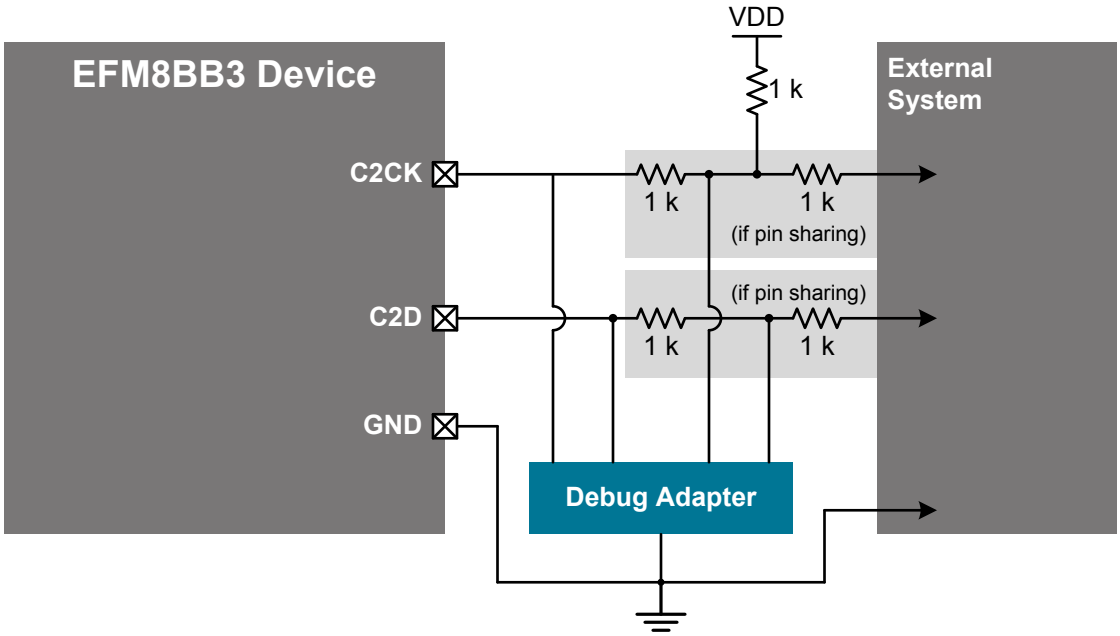


Figure 5.2. Debug Connection Diagram

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
29	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2
30	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.9 CLU3A.9	XTAL2
31	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
32	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
Center	GND	Ground			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.13 CMP0P.9 CMP0N.9
19	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU0A.15 CLU1B.12 CLU2A.12	ADC0.12
20	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU0B.14 CLU1A.13 CLU2B.13	ADC0.11
21	P1.4	Multifunction I/O	Yes	P1MAT.4 CLU0A.14 CLU1A.12 CLU2B.12	ADC0.10
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3
29	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
11	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
12	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
13	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.12 CMP1P.6 CMP1N.6
14	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5
15	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13	ADC0.10 CMP1P.4 CMP1N.4
16	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12	ADC0.9 CMP1P.3 CMP1N.3
17	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
24	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8 CLU3B.10	ADC0.2 CMP0P.2 CMP0N.2

7.2 QFN32 PCB Land Pattern

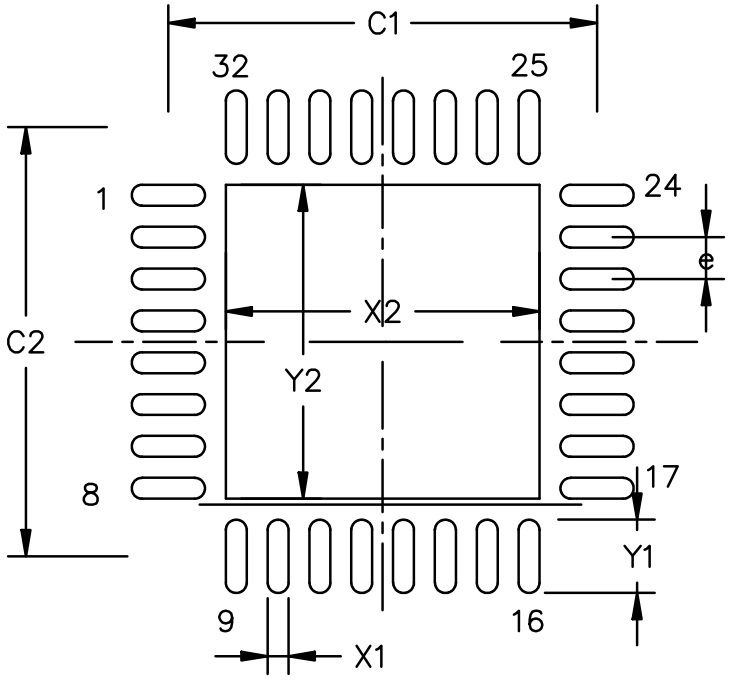


Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	—	4.10
C2	—	4.10
X1	—	0.2
X2	—	3.0
Y1	—	0.7
Y2	—	3.0
e	—	0.4

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.20	
ccc		0.10	
ddd		0.20	
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

Dimension	Min	Typ	Max
e		0.40 BSC	
e1		0.45 BSC	
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10.3 QSOP24 Package Marking

Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

11. Revision History

11.1 Revision 1.01

October 21st, 2016

Updated Figure 2.1 EFM8BB3 Part Numbering on page 2 to include the I-grade description.

Updated QFN24 center pad stencil description.

11.2 Revision 1.0

September 6th, 2016

Filled in all TBD values in 4. Electrical Specifications.

Added a note regarding which DACs are available to Table 2.1 Product Selection Guide on page 2.

Added specifications for 4.1.16 SMBus.

Added bootloader pinout information to 3.10 Bootloader.

Added CRC Calculation Time to 4.1.4 Flash Memory.

11.3 Revision 0.4

May 12th, 2016

Filled in TBD values for DAC Integral Nonlinearity in Table 4.12 DACs on page 26.

Added I-grade devices.

Adjusted the Total Current Sunk into Supply Pin and Total Current Sourced out of Ground Pin specifications in 4.3 Absolute Maximum Ratings.

Added Operating Junction Temperature specification to 4.3 Absolute Maximum Ratings.

11.4 Revision 0.3

February 10th, 2016

Added EFM8831F16G-A-QFN24 to Table 2.1 Product Selection Guide on page 2.

Updated Figure 5.2 Debug Connection Diagram on page 34 to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added mention of the pre-programmed bootloader in 1. Feature List.

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in 3.10 Bootloader.

Updated all part numbers to revision B.

Adjusted C1, C2, X2, Y2, and Y1 maximums for 7.2 QFN32 PCB Land Pattern.

Adjusted package markings for QFN32 and QSOP24 packages.

Filled in TBD minimum and maximum values for DAC Differential Nonlinearity in Table 4.12 DACs on page 26.

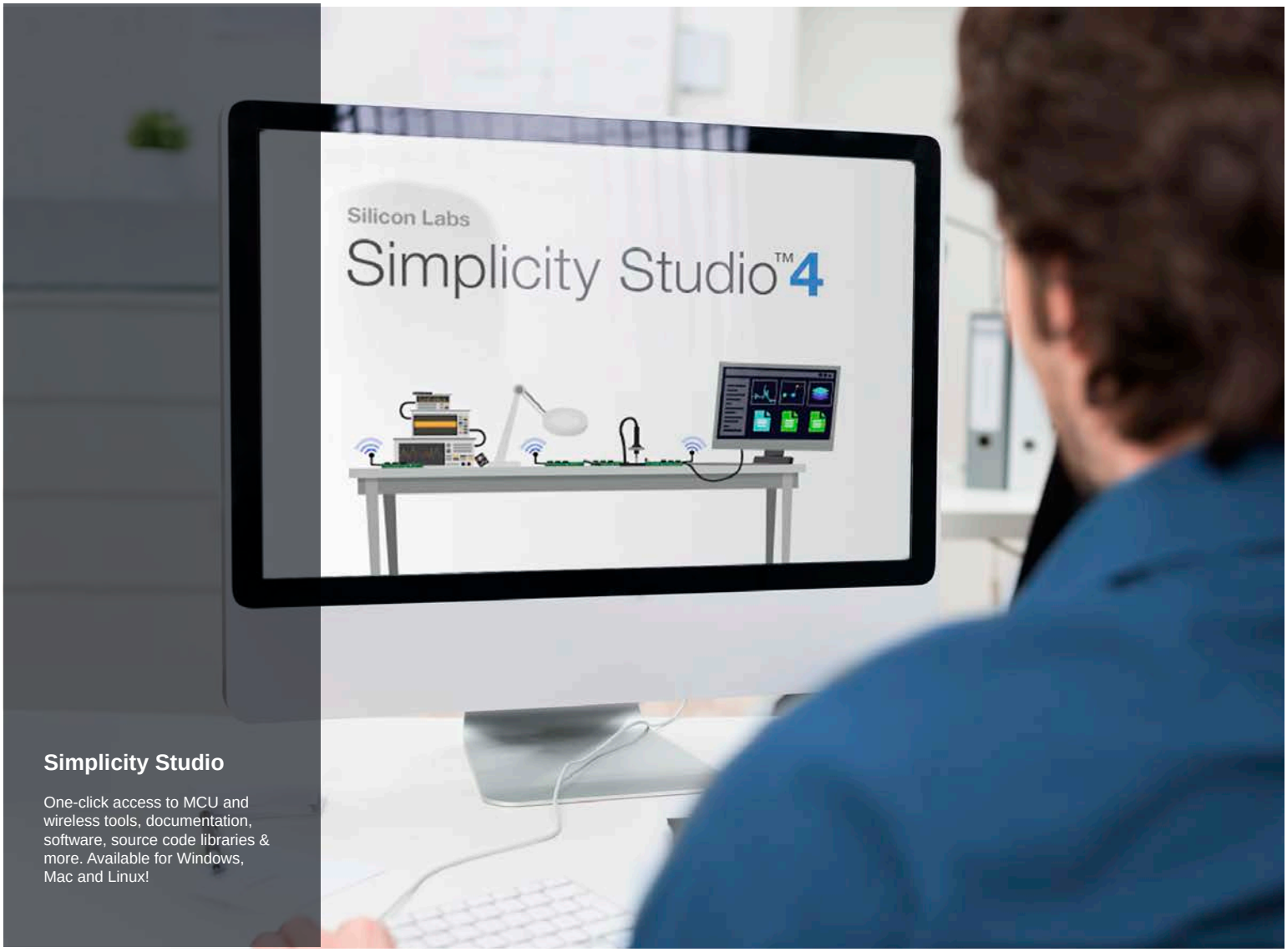
11.5 Revision 0.2

Added information on the bootloader to 3.10 Bootloader.

Updated some characterization TBD values.

11.6 Revision 0.1

Initial release.



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